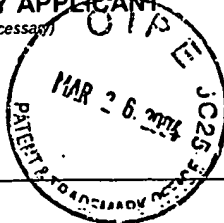


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Application Number 10/666169
Filing Date September 19, 2003
First Named Inventor Jas, Abhijit
Group Art Unit 2816
Examiner Name Unknown

Sheet 1 of 1

Attorney Docket No: 884.911US1

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R. S. Gupta

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First Named Inventor Jas, Abhijit

Group Art Unit Unknown

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R Stephen Deline

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